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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY, DOCKET NO. GRA01 P-423 **APPLICANTS**

SERIAL NO. 10/762,837

INFORMATION DISCLOSURE

David M. Mitteer et al.

January 22, 2004

FILING DATE

GROUP 2835

STATEMENT BY APPLICANT (Use several sheets if necessary)

U.S. PATENT DOCUMENTS

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

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